

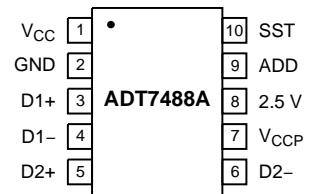


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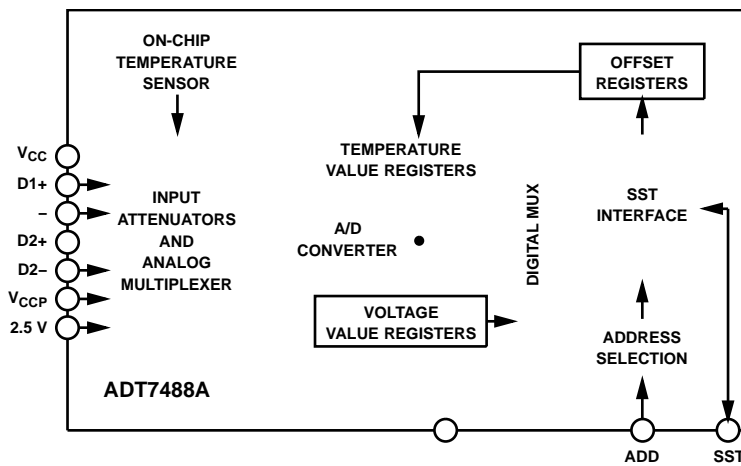
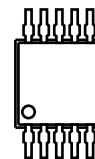
MSOP-10
CASE 846AC

PIN ASSIGNMENT



(Top View)

MARKING DIAGRAM



ORDERING INFORMATION

See detailed ordering and shipping information in the package dimensions section on page 12 of this data sheet.

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Table 1. PIN ASSIGNMENT

| Pin No. | Mnemonic | Type | Description |
|---------|------------------|----------------------|--|
| 1 | V _{CC} | Power Supply | 3.3 V ±10%. V _{CC} is also Monitored through this Pin |
| 2 | GND | Ground | Ground Pin |
| 3 | D1+ | Analog Input | Positive Connection to Remote 1 Temperature Sensor |
| 4 | D1- | Analog Input | Negative Connection to Remote 1 Temperature Sensor |
| 5 | D2+ | Analog Input | Positive Connection to Remote 2 Temperature Sensor |
| 6 | D2- | Analog Input | Negative Connection to Remote 2 Temperature Sensor |
| 7 | V _{CCP} | Analog Input | Processor Core Voltage Monitor |
| 8 | 2.5 V | Analog Input | 2.5 V Supply Monitor |
| 9 | ADD | Digital Input | SST Address Select |
| 10 | SST | Digital Input/Output | SST Bidirectional Data Line |

Table 2. ABSOLUTE MAXIMUM RATINGS

| Parameter | Rating | Unit |
|-----------|--------------|------|
| | 4.0 | V |
| | 3.6 | V |
| | -0.3 to +3.6 | V |
| | ±5.0 | mA |
| | ±20 | mA |
| | 150 | °C |
| | -65 to +150 | °C |
| | 260 300 | °C |
| | 1,500 | V |

stress ratings only. Functional operation above the

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Table 4. ELECTRICAL CHARACTERISTICS

($T_A = T_{MIN}$ to T_{MAX} , $V_{CC} = V_{MIN}$ to V_{MAX} , unless otherwise noted)

| Parameter | Test Conditions/Comments | Min | Typ | Max | Unit |
|--------------------------------|--------------------------|-----|-----|-----|------|
| Power Supply | | | | | |
| Supply Voltage, V_{CC} | | 3.0 | 3.3 | 3.6 | V |
| Undervoltage Lockout Threshold | | - | 2.8 | - | |

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Table 4. ELECTRICAL CHARACTERISTICS (continued)
 ($T_A = T_{MIN}$ to T_{MAX} , $V_{CC} = V_{MIN}$ to V_{MAX} , unless otherwise noted)

| Parameter | Test Conditions/Comments | Min | Typ | Max | Unit |
|--|--|-----------------------|-----------------------|------------------------|---------|
| SST Timing | | | | | |
| Bitwise Period, t_{BIT} | | 0.495 | – | 500 | μ s |
| High Level Time for Logic 1, t_{H1} (Note 2) | t_{BIT} Defined in Speed Negotiation | $0.6 \times t_{BIT}$ | $0.75 \times t_{BIT}$ | $0.8 \times t_{BIT}$ | μ s |
| High Level Time for Logic 0, t_{H0} (Note 2) | | $0.2 \times t_{BIT}$ | $0.25 \times t_{BIT}$ | $0.4 \times t_{BIT}$ | μ s |
| Time to Assert SST High for Logic 1, $t_{SU, HIGH}$ | | – | – | $0.2 \times t_{BIT}$ | μ s |
| Hold Time, t_{HOLD} (Note 3) | See SST Specification Rev 1.0 | – | – | $0.5 \times t_{BIT-M}$ | μ s |
| Stop Time, t_{STOP} | Device Responding to a Constant Low Level Driven by Originator | $1.25 \times t_{BIT}$ | $2 \times t_{BIT}$ | $2 \times t_{BIT}$ | μ s |
| Time to Respond After a Reset, t_{RESET} | | – | – | 0.4 | ms |
| Response Time to Speed Negotiation After Powerup | Time after Powerup when Device Can Participate in Speed Negotiation | – | 500 | – | μ s |

1. Guaranteed by design, not production tested.
2. Minimum and maximum bit times are relative to t_{BIT} defined in the timing negotiation pulse.
3. Device is compatible with hold time specification as driven by SST originator.

TYPICAL PERFORMANCE CHARACTERISTICS

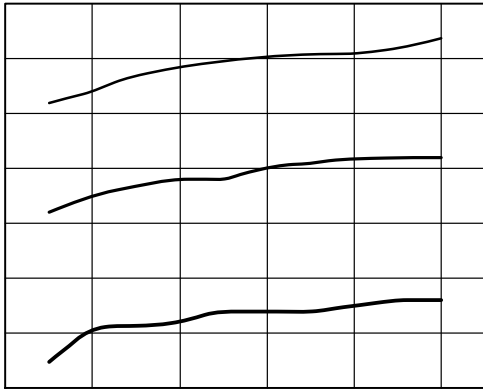


Figure 2. SST O/P Level vs. Supply Voltage

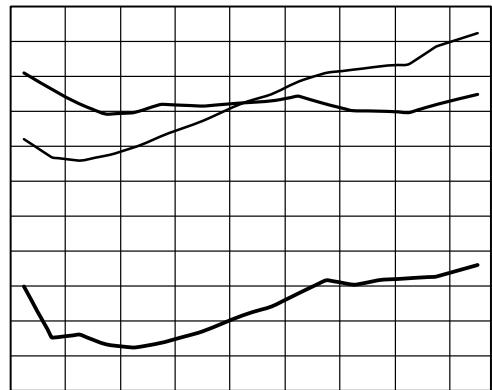


Figure 3. Supply Current vs. Temperature

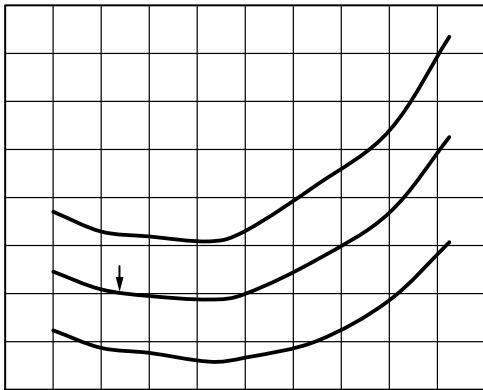


Figure 4. Local Temperature Error

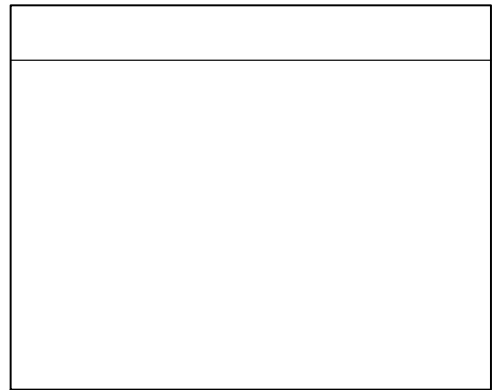


Figure 5. SST O/P Level vs. Temperature

Figure 6. Supply Current vs. Voltage

Figure 7. Remote Temperature Error

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Product Description

The ADT7488A is a temperature- and voltage-monitoring device. The ADT7488A can monitor the temperature of two remote sensor diodes, plus its own internal temperature. It can

Table 7. 16-BYTE DIB DETAILS

| Byte | Name | Value | Description |
|------|-----------------------|--------------|--|
| 0 | Device Capabilities | 0xc0 | Fixed Address Device |
| 1 | Version/Revision | 0x10 | Meets Version 1 of SST Specification |
| 2, 3 | Vendor ID | 00x11d4 | Contains Company ID Number in Little Endian Format |
| 4, 5 | Device ID | 0x7488 | Contains Device ID Number in Little Endian Format |
| 6 | Device Interface | 0x01 | SST Device |
| 7 | Function Interface | 0x00 | Reserved |
| 8 | Reserved | 0x00 | Reserved |
| 9 | Reserved | 0x00 | Reserved |
| 10 | Reserved | 0x00 | Reserved |
| 11 | Reserved | 0x00 | Reserved |
| 12 | Reserved | 0x00 | Reserved |
| 13 | Reserved | 0x00 | Reserved |
| 14 | Revision ID | 0x05 | Contains Revision ID |
| 15 | Client Device Address | 0x48 to 0x4a | Dependent on the State of Address Pin |

Ping()

The Ping() command verifies if a device is responding at a particular address. The ADT7488A shows a valid non-zero FCS in response to the Ping() command when correctly addressed.

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12 V, and the processor core voltage (V_{CCP}) without any external components.

To allow for the tolerance of these supply voltages, the ADC produces a specific output for each nominal input voltage and therefore has adequate headroom to cope with overvoltage. The full-scale voltage that can be recorded for each channel is shown in Table 10.

Table 10. MAXIMUM REPORTED INPUT VOLTAGES

| Voltage Channel | Full-scale Voltage |
|-----------------|--------------------|
|-----------------|--------------------|

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urrent I . The currents through the temperature diode are switched between I and $N1 \times I$, giving ΔV_{BE1} , and then between I and $N2 \times I$, giving ΔV_{BE2} . The temperature can then be calculated using the two ΔV_{BE} measurements. This method can also cancel the effect of series resistance on the temperature measurement. The resulting ΔV_{BE} waveforms are passed through a 65 kHz low-pass filter to remove noise and then through a chopper-stabilized amplifier to amplify

and rectify the waveform, producing a dc voltage proportional to ΔV_{BE} . The ADC digitizes this voltage, and a temperature measurement is produced. To reduce the effects of noise, digital filtering is performed by averaging the results of 16 measurement cycles for low conversion rates. Signal conditioning and measurement of the internal temperature sensor is performed in the same manner.

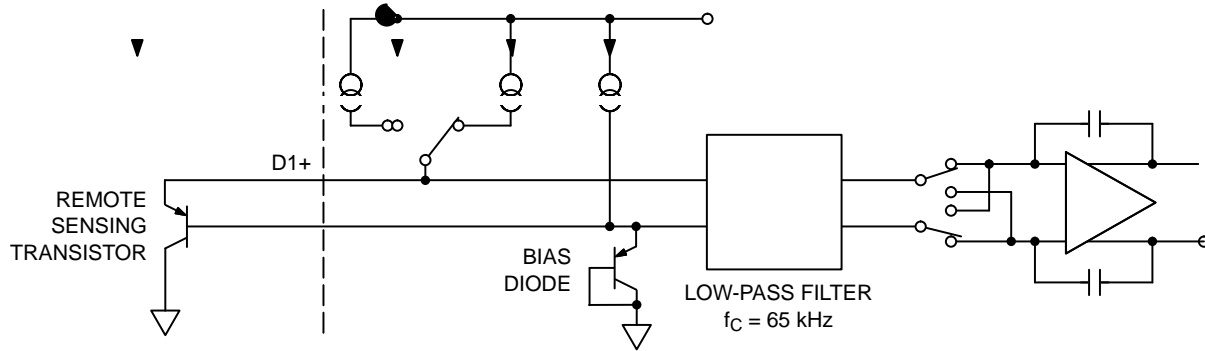
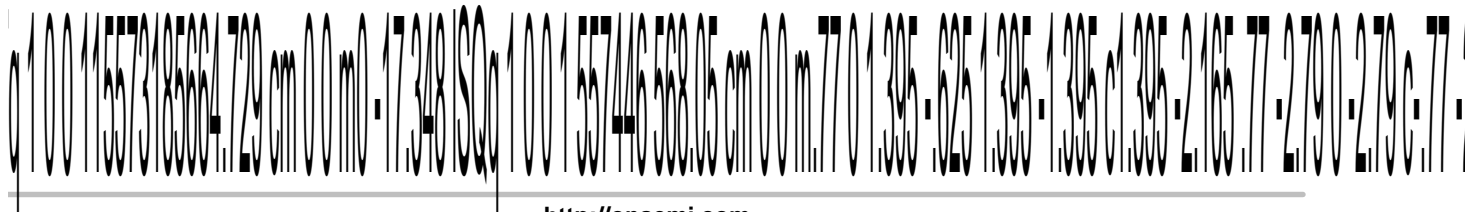


Figure 15. Signal Conditioning for Remote Diode Temperature Sensors



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connected to the D+ input. If an NPN transistor is used, the emitter is connected to the D- input and the base is connected to the D+ input.

Figure 16 shows how to connect the ADT7488A to an NPN or PNP transistor for temperature measurement. To prevent ground noise from interfering with the measurement, the more negative terminal of the sensor is not referenced to ground, but is biased above ground by an internal diode at the D- input.

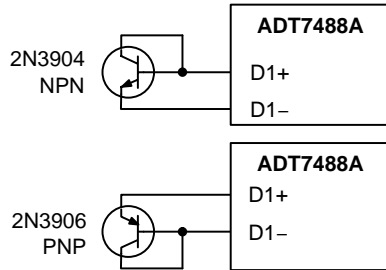


Figure 16. Connections for NPN and PNP Transistors

The ADT7488A shows an external temperature value of

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